PSMN6R0-30YL

N-channel TrenchMOS logic level FET

Rev. 03 — 4 Januari 2010

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in industrial and communications applications.

1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

1.3 Applications

- Class-D amplifiers
- DC-to-DC converters

- Motor control
- Server power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit		
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	30	V		
I _D	drain current	$T_{mb} = 25 ^{\circ}\text{C}; V_{GS} = 10 \text{V};$ see <u>Figure 1</u>	-	-	79	Α		
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	55	W		
Dynamic	characteristics							
Q_{GD}	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 10 \text{ A};$	-	3.08	-	nC		
Q _{G(tot)}	total gate charge	V _{DS} = 12 V; see <u>Figure 14</u> and <u>15</u>	-	11	-	nC		
Static ch	Static characteristics							
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	4.26	6	mΩ		



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb (D
3	S	source		
4	G	gate	9	
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PSMN6R0-30YL	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	30	V
V_{DGR}	drain-gate voltage	$T_j \ge 25$ °C; $T_j \le 175$ °C; $R_{GS} = 20$ kΩ	-	30	V
V_{GS}	gate-source voltage		-20	20	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u>	-	56	Α
		V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u>	-	79	Α
I_{DM}	peak drain current	t _p ≤ 10 μs; pulsed; T _{mb} = 25 °C; see <u>Figure 3</u>	-	292	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	55	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-dr	rain diode				
Is	source current	T _{mb} = 25 °C	-	73	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	292	Α
Avalanche	e ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 73 A; V_{sup} ≤ 30 V; R_{GS} = 50 Ω; unclamped	-	26	mJ

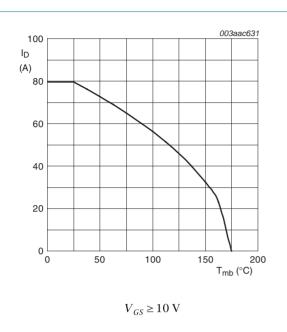


Fig 1. Continuous drain current as a function of mounting base temperature

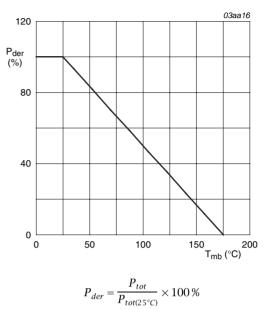
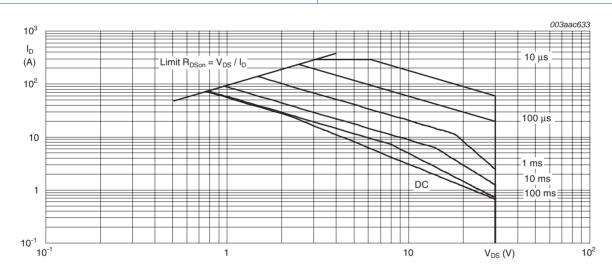


Fig 2. Normalized total power dissipation as a

function of mounting base temperature



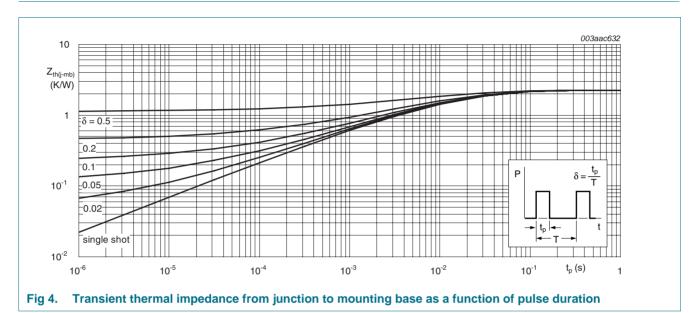
 $T_{mb} = 25 \,^{\circ}C; I_{DM}$ is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j\text{-}mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	1.4	2.25	K/W



6. Characteristics

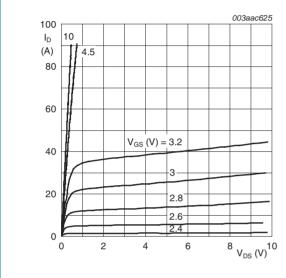
Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 20 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}; t_{av} = 100 \text{ ns}$	35	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
		$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^{\circ}C$	27	-	-	V
$\begin{array}{c} V_{GS(th)} & \text{gate-source threshold} \\ & \text{voltage} \end{array}$		I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C; see <u>Figure 11</u> and <u>12</u>	1.3	1.7	2.15	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 150 \text{ °C}$; see Figure 12	0.65	-	-	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see Figure 12	-	-	2.45	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	100	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nΑ
		$V_{GS} = -16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nΑ
R _{DSon}	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C}$	-	6.18	7.87	mΩ
	resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 ^{\circ}\text{C}; \text{ see } \underline{\text{Figure } 13}$	-	-	10.5	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	4.26	6	mΩ
R_G	gate resistance	f = 1 MHz	-	0.63	1.5	Ω
Dynamic o	characteristics					
Q _{G(tot)} total g	total gate charge	$I_D = 10 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see <u>Figure 14</u> and <u>15</u>	-	11	-	nC
		I_D = 10 A; V_{DS} = 12 V; V_{GS} = 10 V; see <u>Figure 14</u> and <u>15</u>	-	24	-	nC
		$I_D = 0 A$; $V_{DS} = 0 V$; $V_{GS} = 10 V$	-	22	-	nC
Q _{GS}	gate-source charge	$I_D = 10 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$;	-	4.2	-	nC
Q _{GS(th)}	pre-threshold gate-source charge	see <u>Figure 14</u> and <u>15</u>	-	2.4	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	1.8	-	nC
Q_{GD}	gate-drain charge		-	3.08	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	$V_{DS} = 12 \text{ V}$; see <u>Figure 14</u> and <u>15</u>	-	2.6	-	V
C _{iss}	input capacitance	$V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}; T_j = 25 \text{ °C};$	-	1425	-	pF
C _{oss}	output capacitance	see Figure 16	-	313	-	pF
C _{rss}	reverse transfer capacitance		-	155	-	pF
t.,	turn-on delay time	$V_{DS} = 12 \text{ V}; R_L = 0.5 \Omega; V_{GS} = 4.5 \text{ V};$	_	25	_	ns
t _{d(on)}	rise time	$V_{DS} = 12 \text{ V}, K_L = 0.3 \Omega, V_{GS} = 4.3 \text{ V},$ $R_{G(ext)} = 4.7 \Omega$	_	43		ns
t _r	turn-off delay time	Closely		31	-	ns
t _{d(off)}	turn-off dalay time					

Characteristics ... continued Table 6.

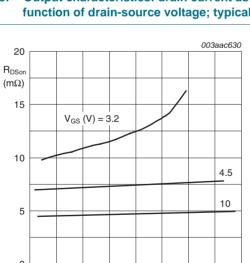
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-dr	ain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 17	-	0.88	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	32	-	ns
Qr	recovered charge	$V_{DS} = 20 \text{ V}$	-	25	-	nC

[1] Tested to JEDEC standards where applicable.



 $T_i = 25 \,^{\circ}C; t_v = 300 \,\mu s$

Output characteristics: drain current as a Fig 5. function of drain-source voltage; typical values



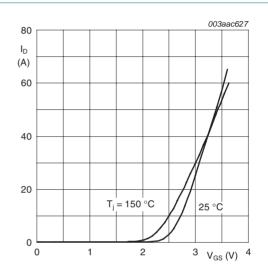
 $T_i = 25 \,^{\circ}C$

20

30 I_D (A) 40

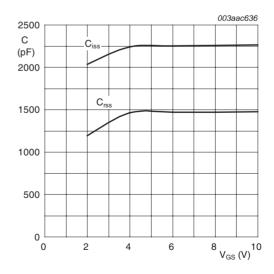
10

Drain-source on-state resistance as a function Fig 7. of drain current; typical values



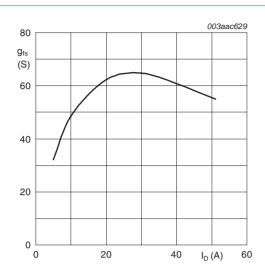
Transfer characteristics: drain current as a Fig 6. function of gate-source voltage; typical values

 $V_{DS} = 10 V$



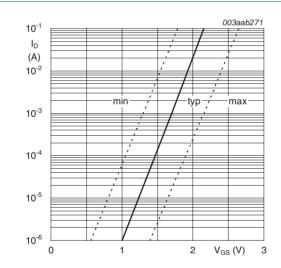
 $V_{DS} = 0 V; f = 1 MHz$

Input and reverse transfer capacitances as a Fig 8. function of gate-source voltage; typical values



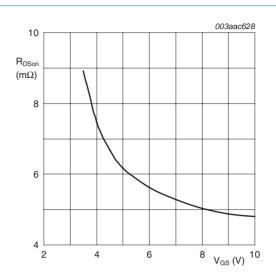
 $T_j = 25 \,{}^{\circ}C; V_{DS} = 15 \, V$

Fig 9. Forward transconductance as a function of drain current; typical values



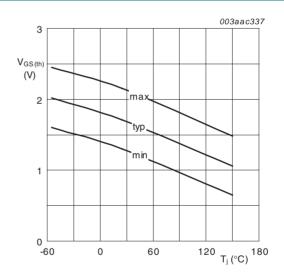
 $T_j = 25 \,{}^{\circ}C; V_{DS} = 5 \, V$

Fig 11. Sub-threshold drain current as a function of gate-source voltage



$$T_j = 25 \,^{\circ}C; I_D = 15A$$

Fig 10. Drain-source on-state resistance as a function of gate-source voltage; typical values



 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 12. Gate-source threshold voltage as a function of junction temperature

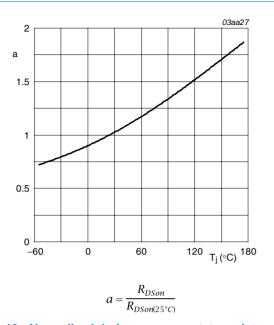


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

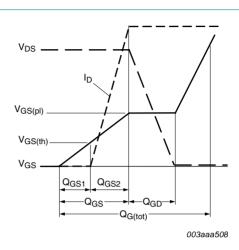
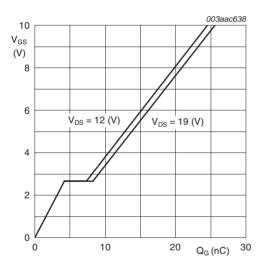
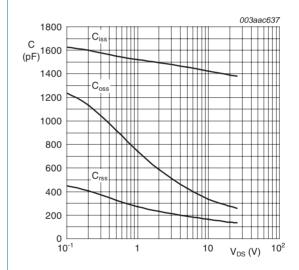


Fig 14. Gate charge waveform definitions



 $T_{j}=25\,^{\circ}C; I_{D}=10A$ Fig 15. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0V; f = 1MHz$

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

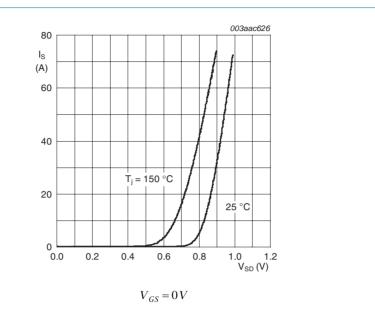
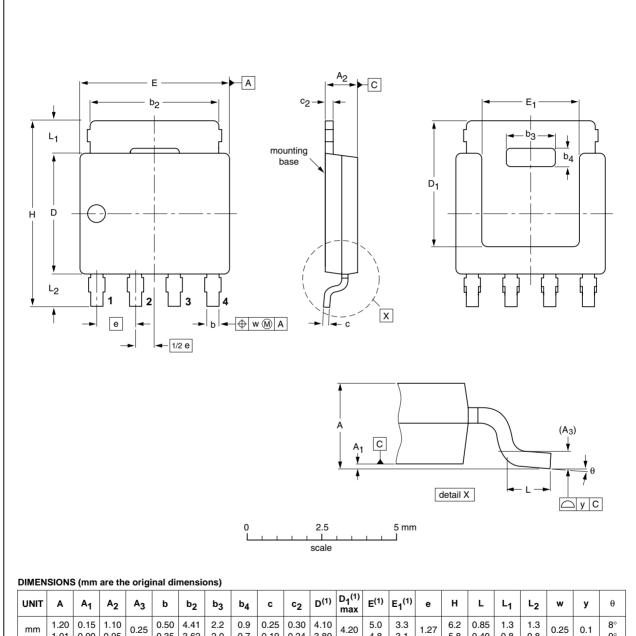


Fig 17. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



UNIT	Α	A ₁	A ₂	A ₃	b	b ₂	b ₃	b ₄	С	c ₂	D ⁽¹⁾	D ₁ ⁽¹⁾ max	E ⁽¹⁾	E ₁ ⁽¹⁾	е	Н	L	L ₁	L ₂	w	у	θ
mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19		4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE	
SOT669		MO-235				04-10-13 06-03-16	

Fig 18. Package outline SOT669 (LFPAK)

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN6R0-30YL_3	20100104	Product data sheet	-	PSMN6R0-30YL_2
Modifications:	 Various cha 	anges to content.		
PSMN6R0-30YL_2	20090105	Product data sheet	-	PSMN6R0-30YL_1
PSMN6R0-30YL_1	20080910	Preliminary data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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PSMN6R0-30YL

N-channel TrenchMOS logic level FET

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